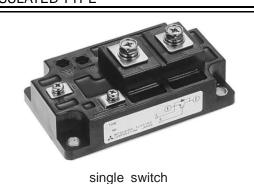


<Hybrid-SiC Modules>

# CMH400HC6-24NFM

HIGH POWER SWITCHING USE **INSULATED TYPE** 



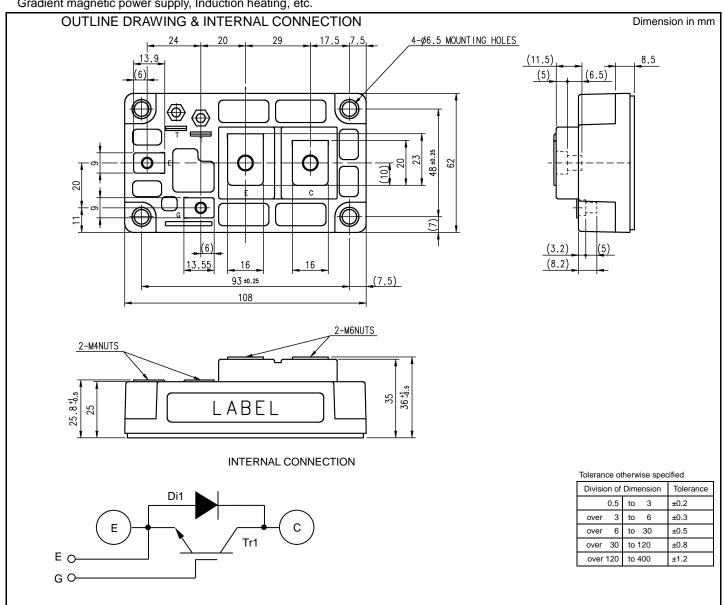
Collector current I<sub>C</sub> ..... 400A Collector-emitter voltage VCES ...... 1 2 0 0 V Maximum junction temperature T<sub>jmax</sub> .....

- •Silicon IGBT + Silicon Carbide Schottky Barrier Diode
- •Flat base Type
- •Copper base plate
- •RoHS Directive compliant
- •Recognized under UL1557, File E323585

#### **APPLICATION**

High frequency switching use(30kHz to 60kHz)

Gradient magnetic power supply, Induction heating, etc.



### HIGH POWER SWITCHING USE

INSULATED TYPE

### MAXIMUM RATINGS ( $T_j$ =25 °C, unless otherwise specified, per module)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1200	V	
V <sub>GES</sub>	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Callactor surrent	DC, T <sub>C</sub> =25 °C (Note2, 4)	400	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	800	A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	2715	W	
I <sub>E</sub> (Note1)	F-n-itto-n-occurrent	DC, T <sub>C</sub> =25 °C (Note2, 4)	400	^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	800	Α	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V	
T <sub>j</sub>	Junction temperature	-	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

### ELECTRICAL CHARACTERISTICS (T<sub>j</sub>=25 °C, unless otherwise specified, per module)

Cymphol	Itam	Conditions		Limits			Unit
Symbol	Item			Min.	Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	20.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	1.4	μΑ
$V_{GE(th)}$	Gate-emitter threshold voltage	I <sub>C</sub> =40 mA, V <sub>CE</sub> =10 V	$I_C$ =40 mA, $V_{CE}$ =10 V		6.0	7.5	V
V	Collector-emitter saturation voltage	I <sub>C</sub> =400 A, V <sub>GE</sub> =15 V (Note5)	T <sub>j</sub> =25 °C	=	3.0	4.5	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>j</sub> =125 °C	=	3.0	-	V
Cies	Input capacitance			-	-	63	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		=	-	5.3	nF
Cres	Reverse transfer capacitance	7			-	1.2	
$Q_G$	Gate charge	V <sub>CC</sub> =600 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =15 V		=	1800	-	nC
t <sub>d(on)</sub>	Turn-on delay time	- V <sub>CC</sub> =600 V, I <sub>C</sub> =400 A, V <sub>GE</sub> =±15 V, $-$ R <sub>G</sub> =3.0 Ω, Inductive load		-	-	300	
tr	Rise time			-	-	200	ns
t <sub>d(off)</sub>	Turn-off delay time			-	-	500	115
t <sub>f</sub>	Fall time			-	-	200	
V=a (Note1)	Emitter-collector voltage	I <sub>E</sub> =400 A, G-E short-circuited (Note5)	T <sub>j</sub> =25 °C	-	1.7	2.2	V
V <sub>EC</sub> (Note1)		Refer to the figure of test circuit	T <sub>j</sub> =125 °C	-	2.1	-	]
Q <sub>C</sub> (Note1)	Total capacitive charge	$V_{CC}$ =600 V, $I_{E}$ =100 A, $V_{GE}$ =±15 V, $R_{G}$ =3.0 $\Omega$ , Inductive load		-	1.5	-	μC
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =600 V, I <sub>C</sub> /I <sub>E</sub> =400 A,		-	10.0	-	1
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}=\pm15 \text{ V}, R_{G}=3.0 \Omega,$		-	28.0	-	mJ
E <sub>rec</sub> (Note1)	Reverse energy per pulse	T <sub>j</sub> =125 °C, Inductive load		-	0.7	-	mJ
r <sub>g</sub>	Internal gate resistance	Per switch		-	0.75	-	Ω

### THERMAL RESISTANCE CHARACTERISTICS (per module)

		,				
Symbol	Item	Conditions	Limits			Unit
			Min.	Тур.	Max.	Offic
$R_{th(j-c)Q}$	Thermal resistance	Junction to case (Note4)	-	-	46	K/kW
$R_{th(j-c)D}$		Junction to case (Note4)	-	-	123	r/KVV
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4, 6)	-	20	-	K/W

Caution; No short-circuit capability is designed.

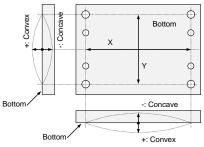
### HIGH POWER SWITCHING USE

#### INSULATED TYPE

#### MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions		Limits			Unit
	item			Min.	Тур.	Max.	Offic
M <sub>t</sub>	Mounting torque	Main terminals M 6	6 screw	1.96	2.45	2.94	N∙m
M <sub>t</sub>	Mounting torque	G/E auxiliary terminals M 4	4 screw	0.98	1.18	1.47	N∙m
Ms	Mounting torque	Mounting to heat sink M 6	6 screw	1.96	2.45	2.94	N∙m
m	mass	-		1	480	ı	g
ec	Flatness of base plate	On the centerline X (Note7)		0	ı	100	um
	I riatiless of base plate	On the centerline Y (Note7)		0	-	100	μm

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (DIODE).
  - 2. Junction temperature  $(T_j)$  should not increase beyond  $T_{j\,m\,a\,x}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature (T<sub>j</sub>) dose not exceed T<sub>jmax</sub> rating.
  - 4. Case temperature (T<sub>c</sub>) and heat sink temperature (T<sub>s</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K).
  - 7. The base plate (mounting side) flatness measurement points (X, Y) are as follows of the following figure.

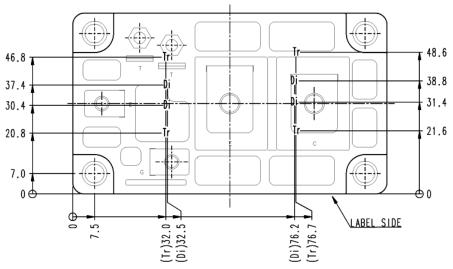


#### RECOMMENDED OPERATING CONDITIONS

RECOMMENDED OF EXAMING CONDITIONS							
Symbol	Itom	Conditions	Limits			Unit	
	Item	Conditions	Min.	Тур.	Max.	Offic	
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	800	V	
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V	
$R_G$	External gate resistance	Per switch	0.78	-	7.8	Ω	

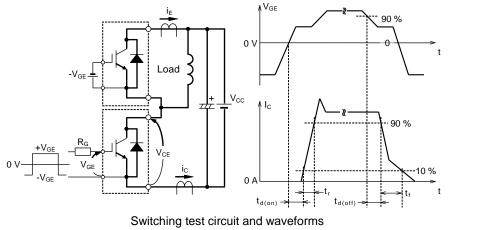
# CHIP LOCATION (Top view)

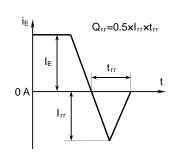
Dimension in mm, tolerance: ±1 mm

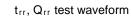


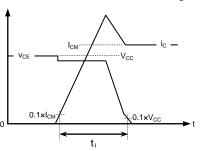
Tr: IGBT, Di: DIODE

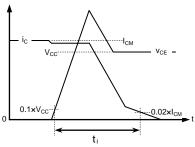
#### **TEST CIRCUIT AND WAVEFORMS**

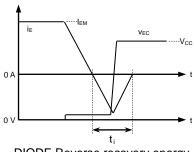












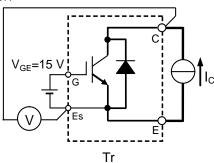
IGBT Turn-on switching energy

IGBT Turn-off switching energy

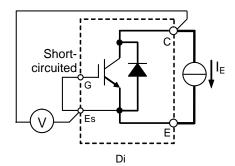
DIODE Reverse recovery energy

Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

### **TEST CIRCUIT**



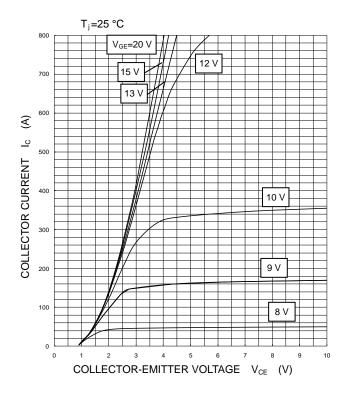
V<sub>CEsat</sub> characteristics test circuit



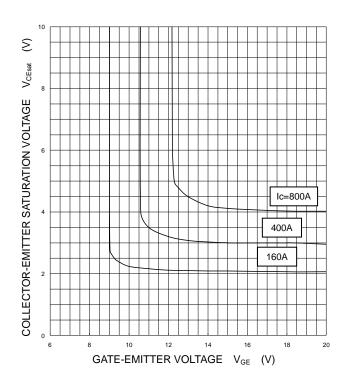
V<sub>EC</sub> characteristics test circuit

#### PERFORMANCE CURVES

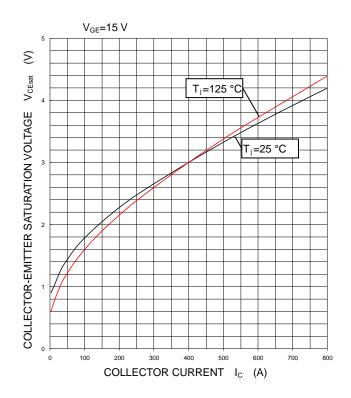
OUTPUT CHARACTERISTICS (TYPICAL)



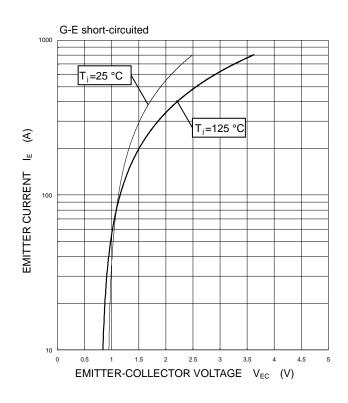
#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



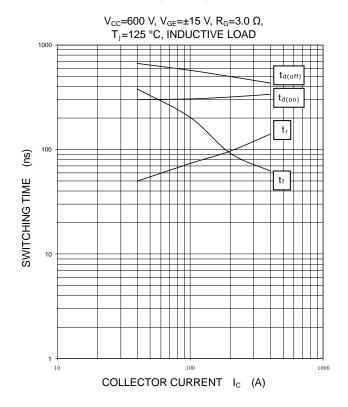
FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)



HIGH POWER SWITCHING USE INSULATED TYPE

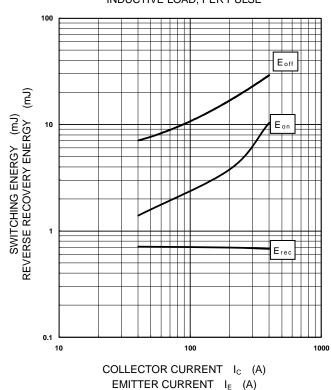
#### PERFORMANCE CURVES

#### HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

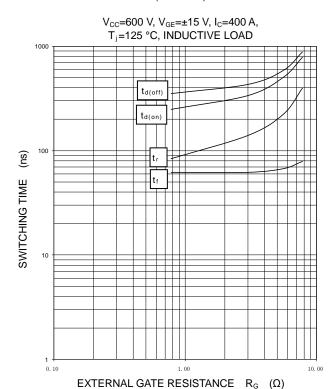


#### HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 $\label{eq:Vcc=600} \begin{aligned} V_{\text{CC}}\!=\!600 \text{ V, } V_{\text{GE}}\!=\!\pm15 \text{ V, } R_{\text{G}}\!=\!3.0 \text{ }\Omega, \text{ } T_{j}\!=\!125 \text{ }^{\circ}\text{C,} \\ \text{INDUCTIVE LOAD, PER PULSE} \end{aligned}$ 

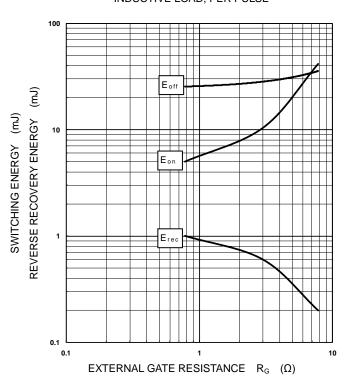


#### HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



#### HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 $V_{CC}$ =600 V,  $V_{GE}$ =±15 V,  $I_{C}$ / $I_{E}$ =400 A,  $T_{j}$ =125 °C, INDUCTIVE LOAD, PER PULSE

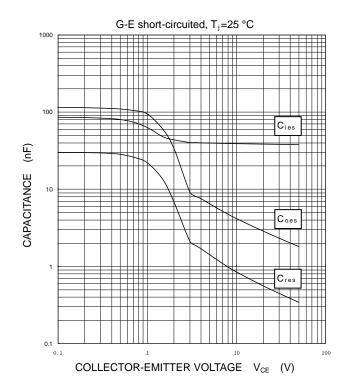


HIGH POWER SWITCHING USE

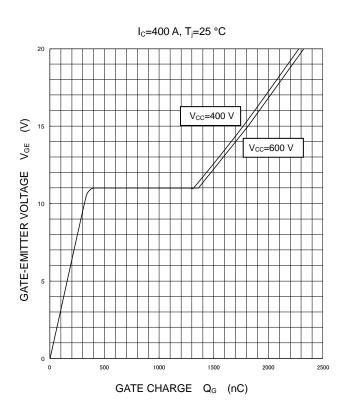
**INSULATED TYPE** 

#### PERFORMANCE CURVES

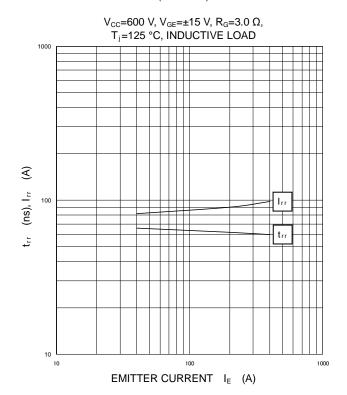
CAPACITANCE CHARACTERISTICS (TYPICAL)



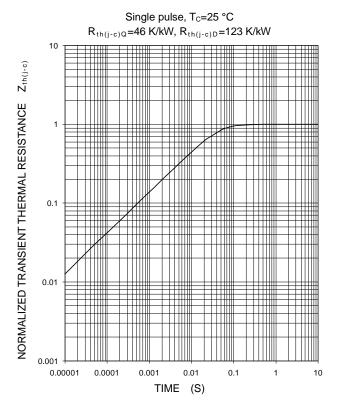
#### GATE CHARGE CHARACTERISTICS (TYPICAL)



#### FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



#### TRANSIENT THERMAL IMPEDANCE CHARACTERISTIC S (MAXIMUM)



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

HIGH POWER SWITCHING USE INSULATED TYPE

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